Form PTO-1449	Docket Number 188122000400	Application Number 10/735,123
INFORMATION DISCLOSURE CITATION IN AN APPLICATION *(Use several sheets if necessary)*	Applicant: Igor KELLER et al.	
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U.S. PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Name	Class	Subclass	Filing Date If Appropriate

FOREIGN PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Country	Class	Subclass	Translation YES	Translation NO

OTHER DOCUMENTS *(including author, title, Date, Pertinent Pages, Etc.)*

Examiner Initials	Ref. No.	Title
RF	1.	R. Arunachalam et al., "TACO: Timing Analysis With COupling", ACM 2000, 4 pgs.
	2.	P. Chen et al., "Miller Factor for Gate-Level Coupling Delay Calculation", IEEE, International Conference on Computer Aided Design, 2000, 7 pgs.
	3.	J. F. Croix et al., "Blade and Razor: Cell and Interconnect Delay Analysis Using Current-Based Models", DAC June 2-6, 2003, Anaheim CA, pp. 386-389.
	4.	F. Dartu et al., "Calculating Worst-Case Gate Delay Due to Dominant Capacitance Coupling", DAC 97, Anaheim CA, 6 pgs.
	5.	P. D. Gross et al., "Determination of Worst-Case Aggressor Alignment for Delay Calculation", ACM 1998, pgs. 212-219.
	6.	I. Keller et al., "A robust cell-level crosstalk delay change analysis", 8 pgs.
	7.	I. Keller et al., "On a robust noise-on-delay cell-level analysis", 7 pgs.
	8.	A. Odabasioglu et al., "PRIMA: Passive Reduced-Order Interconnect Macromodeling Algorithm", IEEE Transactions on Computer Aided Design of Integrated Circuits and Systems, vol. 17, no.8, Aug. 1998, pgs. 645-654.
	9.	V. Raghavan et al., "AWESpice: A General Tool for the Accurate and Efficient Simulation of Interconnect Problems", 29th ACM/IEEE Design Automation Conference, paper 6.3, 1992, pgs. 87-92.
	10.	K. Shepard, "Design Methodologies for Noise in Digital Integrated Circuits", 35th Design Automation Conference, ACM 1998, 6 pgs.
	11.	S. Sirichotiyakul et al., "Driver Modeling and Alignment for Worst-Case Delay Noise", IEEE Trans. on Very Large Scale Integration v. 11, no. 2, April 2003, 6 pgs.
RF	12.	V. Zolotov et al., "Noise Propagation and Failure Criteria for VLSI Designs", IEEE 2002, 8 pgs.

EXAMINER: /Russell Frejd/	DATE CONSIDERED: 07/17/2006

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